

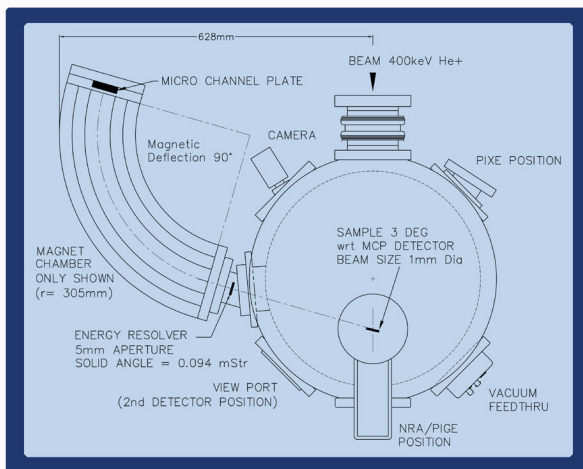
High Resolution RBS Analysis

FOR NANOTECHNOLOGY APPLICATIONS

Angstrom level thin film analysis with high energy RBS, channeling, PIXE, ERD, and NRA in one instrument



High Resolution RBS Detector attached to the model RC43 Analysis Endstation with angle variability of $\pm 5^\circ$ at each 90° and 135° port.



Scattered particles are energy analyzed by the 90° magnet followed by a position sensitive micro channel plate detector. The resolution and detector solid angle can be modified by the choice of detector entrance aperture.



Model RC43 Analysis Endstation for PIXE, NRA and RBS with Channeling.



NEC tandem Pelletrons from 1MV to 3MV are designed for maximum versatility and ease of use for a wide range of analysis techniques.